

Tencor Alpha-Step 200 Contact Profilometer

DESCRIPTION:

- For applications in thin or thick films
- Vertical ranges:
 - 160 kÅ (kilo Angstrom range)
 - 160 μm (micrometer range)
- Horizontal range 10,000 μm
- Vertical resolution:
 - 5Å (kilo Angstrom range)
 - 5 nm (micrometer Range)
- Horizontal resolution: 400
- Stylus force may be set as low as 1mg
- Can be used to measure samples up to 21mm thick (Z), 150mm (X), 81mm (Y)



LOCATION: IEEC RELIABILITY LAB

[CONTACT US](#)

CONTACTS

For more information or to arrange for the use of this equipment, contact any of the IEEC staff members listed below:

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